FORM PTO-1449 (REV. 7-80)

## U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

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David Hoyle, et al.

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			U.S. PATI	ENT DOCUMENT	`S			
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HCO	AA	4,109,310	8/22/78	England, e	t al. 364	200		
02.H	AB	4,512,018	4/16/85	Phelps, et	al. 370	112		
D7H	AC	4,523,276	6/11/85	Maejima, e	t al. 364	200		
AC0	AD	4,858,113	8/15/89	Saccard	i 364	200		
DTH	AE	5,446,482	8/29/95	Van Aken,	et al. 345	199		
024	AF	5,809,288	9/15/98	Balmei	395	553		
HTO	AG	5,835,793	11/10/98	Li, et al	. 395	898		
HTO	AH	5,961,635	10/5/99	Guttag, et	al. 712	221		
	AI							
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		DOCUMENT NUMBER	DATE	COUNT	RY CLASS	SUB- CLASS	TRANS Yes	SLATIOI N
OTH	BA	GB 2 229 832 9003070.1	10/3/90 2/12/90	UK	G06F	7/00		
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		OTHER DOCUM	ENTS (Includin	g Author, Title, Do	ite, Pertinent Pages, E	itc.)		
07H	CA	D.K. DuBose, et al.; A Microcoded RISC, Computer Society of the IEEE, Proc. 19 <sup>th</sup> Annual Workshop on Microprogramming Micro.19, Oct. 15-17, 1986, NY, ACM SIGMICRO Newsletter, Vol. 17, No. 4, Dec., 1986, pgs. 124-128.						
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